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FORM	First Named Inventor	July 21, 2003								
FORW		Luan C. Tran								
(to be used for all correspondence after initial		2811								
	Examiner Name	Jennifer Kennedy								
Total Number of Pages in This Submission	Attorney Docket Number	er MI22-2358								
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No
Filing Date July 21, 2003
Inventor Luan C. Tran
Assignee Micron Technology, Inc.
Group Art Unit
priority Examiner Kennedy, Jennifer J.
Attorney's Docket No MI22-2358
Title: Methods of Forming Semiconductor Constructions

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR § 1.56. Copies of the cited art are included with the exception of U.S. patents and published U.S. applications (1276 OG 55). No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing date of a first Office Action, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: *Movember* 11, 2003

Jennifer J. Taylor, Ph.D

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